


**INFORMATION DISCLOSURE  
CITATION**

ATTY. DOCKET NO.

4105-19

SERIAL NO.

10/615,415

APPLICANT

ONOE et al.

FILING DATE

July 9, 2003

TC/A.U.

2627

(Use several sheets if necessary)

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TT	62th Japan Society of Applied Physics Lecture Meeting (2001.9 Aichi Institute of Technology) 12p-ZR-2.

\*Examiner

/Thang Tran/

Date Considered

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